Abstracts

Broad-Band Noise Mechanisms and Noise Measurements of Metal Semiconductor Junctions

A. Jelenski, E.L. Kollberg and H.H.G. Zirath. "Broad-Band Noise Mechanisms and Noise Measurements of Metal Semiconductor Junctions." 1986 Transactions on Microwave Theory and Techniques 34.11 (Nov. 1986 [T-MTT]): 1193-1201.

Classic work on optimized heterodyne receivers has concentrated on the network aspects of mixers with limited emphasis on device properties. We present experimental results of GaAs Schottky-barrier diode noise measurements in the frequency range from 0.1 to 88 GHz and a detailed analysis of noise generation in these diodes which can explain the observed current and frequency dependence.

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